

KITANO.012AUS

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Hitoshi Kitayoshi	)	Group Art Unit
Serial No.	:	New Application	)	#8/A
Filed	:	Concurrently Herewith	)	2
For	:	FIELD DISTRIBUTION MEASURING METHOD AND APPARATUS	)	11-16-2
Examiner	:	Unknown	)	
<hr/>				

PRELIMINARY AMENDMENT

Hon. Commissioner  
of Patents and Trademarks  
Washington, D.C. 20231

Dear Sir:

This amendment is submitted for the above-identified patent application which is an entrance application of international patent application No. PCT/JP01/03344 filed April 19, 2001. Please make the following changes.

IN THE CLAIMS:

Please cancel all of the pending claims, Claims 1-10 and add the following new claims, Claims 11-24.

11. A field distribution measuring method for measuring an electric field or a magnetic field by a probe measuring at a plurality of sampling points while continuously sweeping, wherein a shift amount of the sampling points is computed, based on a spurious spectrum generated by a displacement between a position of the probe and a measuring timing, and a distribution of the